## A X- and W-band EPR study of carbon related dangling bonds in SiCN and SiCN/Fe ceramics

Andronenko S.I. 1, Misra S.K. 2

sergey.andronenko@gmail.com

SiCN is a new class of materials for high-temperature electronics. Magnetic properties of SiCN materials doped with different transition metal ions can vary from paramagnetic to superparamagnetic and to ferromagnetic [1]. Superparamagnetic materials are potentially useful in developing high-temperature sensor devices [2], Consequently, investigation of SiCN ceramics and its conductive and magnetic derivatives is currently of great interest. The SiCN ceramics consists of SiCN nanoparticles (Si<sub>3</sub>N<sub>4</sub> -like structure), which are covered with graphene layers [1,2]. Further, sp<sup>2</sup> and sp<sup>3</sup>-carbon related dangling bonds, which are usually formed in this graphene layers [3,4], could be investigated by EPR, a powerful technique to detect various types of paramagnetic defects. The Xband narrow EPR line near g = 2.00 is due to two carbon related dangling bonds [3]. It is structureless at X-band, but at W-band these signals become resolved. The EPR study of SiCN ceramics, annealed at 1100° C was carried out at 300 K at W-band (93.96 GHz). The two observed Wband EPR lines are due to carbon-related  $sp^2$  and  $sp^3$ -dangling bonds. The EPR line with g=2.0033 is associated with  $sp^3$ -carbon related dangling bonds in amorphous carbon and the EPR line with g =2.0011 is associated with sp<sup>2</sup>-carbon related dangling bonds, which are located in broken aromatic rings of graphene layers, similar to that, observed in treated diamond [5]. Relative intensities of these two EPR lines depends on annealing temperature.

This research was supported by the Natural Sciences and Engineering Research Council of Canada (NSERC) (SKM); SIA is grateful for partial support of research project, allocated to Kazan Federal University for the state assignment (#3.2166.2017/4.6).

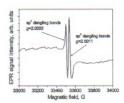


Figure 1. W-band EPR spectrum of SiCN/Fe ceramics in the range 33,000 - 34,000 G.

## References

- S. K. Misra, S. Andronenko, I. Gilmutdinov, R. Yusupov, Appl. Magn. Reson. (2018) 49,1397.
- 2. A. Leo, S. Andronenko, I. Stiharu, R. B. Bhat, Sensors (2010) 10, 1338.
- S.I. Andronenko, I. Stiharu, S.K Misra, J. Appl. Phys. (2006) 99, 113907.
- 4. S.I. Andronenko, A.A. Rodionov, S.K. Misra, Appl. Magn. Reson. (2018) 49,335.
- O.E. Andersson, B.L.V. Prasad, H. Sato, T. Enoki, Y. Hishiyama, Y. Kabaragi, M. Yoshikawa, S. Bandow, Phys. Rev. B (1998) 58, 16387.

<sup>&</sup>lt;sup>1</sup> Institute of Physics, Kazan Federal University, Kazan, Russian Federation, 420008

<sup>&</sup>lt;sup>2</sup> Department of Physics, Concordia University, Montreal, Qc, H3G 1M8, Canada